SoC TEST SYSTEMS

S210 LSI Test System

The S210 is a multi-LSI test system offering high-speed throughput, low cost, and space savings. Its function tests are performed with the highest throughput in the industry. The S210 is more than a simple logic tester, as when optional AD/DA modules are added, the test system can be used in a wide variety of applications such as 1-bit DAC audio analog tests.

●Specifications
・ 20/40 MHz test rates
・ 512 I/O pins
・ Per-Pin TG
・ Multi-test site 　 32 DUT/ST

●Target Device
DVD, CD-RW, CD-ROM, PHS, MCU, LCD drivers, LTPS, System LSIs

DOUBLE SIDE WAFER PROBER

WS50 Double Side Wafer Prober

Since the WS50 provides ideal test methods for testing high-voltage devices, it is capable of high-accuracy testing and high reliability using a newly-developed contact method for both sides probing of wafers.

●Specifications
・ High-accuracy ultra-low ON resistance tests (using Id = 100 A)
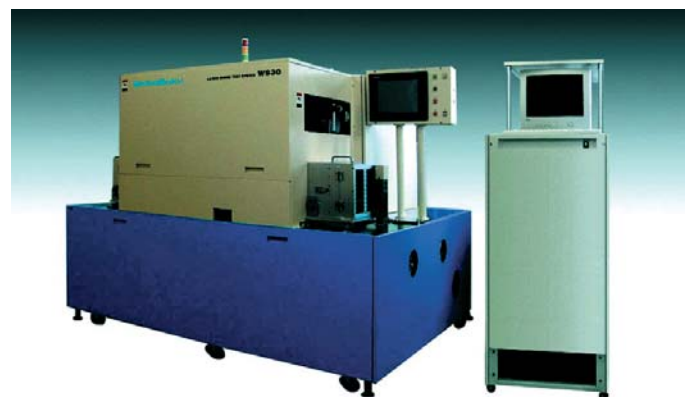・ Avalanche switching characteristics tests on wafers

OPTICAL DEVICES TEST SYSTEMS

WS30 Laser Diode Test System

The WS30 uses the index parallel method to enable high-speed throughput testing of multiple devices. It is also an ideal test system for devices that must be inspected in various separated test categories.

●Specifications
・ Supports dual-wavelength LDs of DVDs and CDs; single-wavelength testing for either type is also possible.
・ Use of a Windows screen enables easy operation and display of characteristics graphs for all test stages.
・ High-speed testing and high-speed processing is possible using simultaneous testing of 2 devices and the index parallel method.

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